



Customer Information Notification

202207020I : MKW40Z/30Z/20Z Reference Manual Update to Rev 1.4.1

Note: This notice is NXP Company Proprietary.

Issue Date: Oct 04, 2022 **Effective date:** Oct 05, 2022

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Management summary

Reference Manual (RM) update for the MKW40Z/30Z/20Z to revision 1.4.1.

Change Category

<input type="checkbox"/> Wafer Fab Process	<input type="checkbox"/> Assembly Process	<input type="checkbox"/> Product Marking	<input type="checkbox"/> Test Process	<input type="checkbox"/> Design
<input type="checkbox"/> Wafer Fab Materials	<input type="checkbox"/> Assembly Materials	<input type="checkbox"/> Mechanical Specification	<input type="checkbox"/> Test Equipment	<input type="checkbox"/> Errata
<input type="checkbox"/> Wafer Fab Location	<input type="checkbox"/> Assembly Location	<input type="checkbox"/> Packing/Shipping/Labeling	<input type="checkbox"/> Test Location	<input type="checkbox"/> Electrical spec./Test coverage
<input type="checkbox"/> Firmware <input checked="" type="checkbox"/> Other: Reference Manual				

PCN Overview

Description

NXP Semiconductors announces a Reference Manual (RM) update for the MKW40Z/30Z/20Z to revision 1.4.1. The Chapter 56 included in the updated document provides a detailed description of the changes.

Changes are summarized below.

Reference Manual Changes:

1. Removed the DTEST_PAGE bitfield from the XCVR_DTEST_CTRL register.
2. Added I2C1 interrupt at 0x0000_0064 in Table 3-6. Interrupt vector assignment in Chip Configuration.
3. DCDC_REG2[DCDC_LOOPCTRL_EN_RCSCALE] added at bit[10:9]. Also updated bit field descriptions of the registers in DCDC Converter(DCDC).
4. Removed test registers: C12, S2 and T3 in Multipurpose Clock Generator (MCG).
5. Updated register information in Universal Asynchronous Receiver/Transmitter (UART0).
6. Updated access value of Key Size(KS) register to RO in LP Trusted Cryptography (LTC).
7. Removed test register Radio System Integration Module(RSIM).

8. Updated access values of the following registers to RW: XCVR_PLL_HPM_CAL_CTRL, XCVR_PLL_LD_HPM_CAL1, and XCVR_PLL_LD_HPM_CAL2 in Transceiver Registers.
9. Updated access value of the BLE_RF_REGS_BLE_PART_ID register to RO in BLE RF Registers.
10. Updated access value of ZLL_SAM_MATCH register to RO and access value of ZLL_FILTERFAIL_CODE register to RW in Zigbee Registers.

The MKW40Z/30Z/20Z Reference Manual revision 1.4 is attached to this notice, and can be found at:

<https://www.nxp.com/products/wireless/multiprotocol-mcus/kinetis-kw40z-2-4-ghz-dual-mode-bluetooth-low-energy-and-802-15-4-wireless-radio-microcontroller-mcu-based-on-arm-cortex-m0-plus-core:KW40Z?fpsp=1&#documentation>

Reason

The Reference Manual has been updated to correct errors and / or provide additional technical clarification on some device features.

Identification of Affected Products

Product identification does not change

Anticipated Impact on Form, Fit, Function, Reliability or Quality

No Impact on form, fit, function, reliability or quality

Additional information

Additional documents: [view online](#)

Contact and Support

For all inquiries regarding the ePCN tool application or access issues, please contact NXP "Global Quality Support Team".

For all Quality Notification content inquiries, please contact your local NXP Sales Support team.

For specific questions on this notice or the products affected please contact our specialist directly:

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NXP Quality Management Team.

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